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U.S. UTILITY Patent Application

PATENT NUMBER and
ISSUE DATE

APPL NUM	FILING DATE	CLASS	SUBCLASS	GAU	EXAMINER
10068152	02/06/2002	324	765	2858	W. H. Johnson

**APPLICANTS: Lee Sang-Eun; Han Jae-Sung; 2829

**CONTINUING DATA VERIFIED:

** FOREIGN APPLICATIONS VERIFIED:

REPUBLIC OF KOREA 2001-8465 02/20/2001

Verified

PG-PUB	DO NOT PUBLISH <input type="checkbox"/>	RESCIND <input type="checkbox"/>	
Foreign priority claimed		<input checked="" type="checkbox"/> yes <input type="checkbox"/> no	ATTORNEY DOCKET NO
35 USC 119 conditions met		<input checked="" type="checkbox"/> yes <input type="checkbox"/> no	8750-17
Verified and Acknowledged Examiner's initials <i>Jah - Hjt</i>			
TITLE : Method of identifying and analyzing semiconductor chip defects			
U.S. DEPT. OF COMM./PAT. & TM-PTO-435L(Rev. 12-94)			

NOTICE OF ALLOWANCE MAILED		Assistant Examiner	CLAIMS ALLOWED	
			Total Claims	Print Claim for O.G
ISSUE FEE		DRAWING		
Amount Due	Date Paid	Sheets Drwg.	Figs. Drwg.	Print Fig.
TERMINAL DISCLAIMER		Primary Examiner		
		Application Examiner		
PREPARED FOR ISSUE				
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